

# CY7C185

# 8K x 8 Static RAM

### **Features**

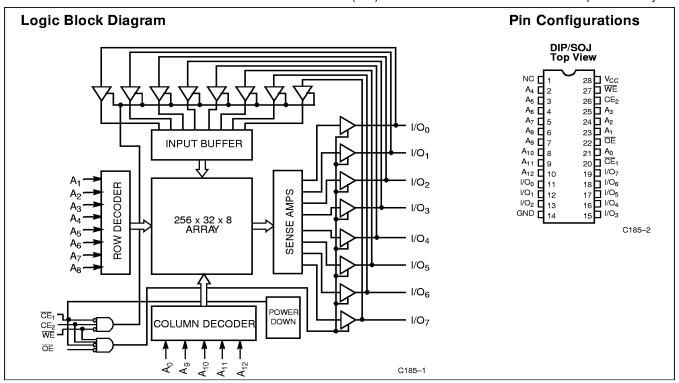
- · High speed
  - 15 ns
- Fast t<sub>DOE</sub>
- Low active power
  - -715 mW
- · Low standby power
  - -220 mW
- · CMOS for optimum speed/power
- Easy memory expansion with  $\overline{CE}_1$ ,  $CE_2$  and  $\overline{OE}$  features
- · TTL-compatible inputs and outputs
- · Automatic power-down when deselected

### **Functional Description**

The CY7C185 is a high-performance CMOS static RAM organized as 8192 words by 8 bits. Easy memory expansion is provided by an active LOW chip enable (CE<sub>1</sub>), an active HIGH chip enable (CE2), and active LOW output enable (OE) and three-state drivers. This device has an automatic power-down feature (CE<sub>1</sub> or CE<sub>2</sub>), reducing the power consumption by 70% when deselected. The CY7C185 is in a standard 300-mil-wide DIP and SOJ package.

An active LOW write enable signal (WE) controls the writing/reading operation of the memory. When  $\overline{CE}_1$  and  $\overline{WE}$  inputs are both LOW and CE2 is HIGH, data on the eight data input/output pins (I/O<sub>0</sub> through I/O<sub>7</sub>) is written into the memory location addressed by the address present on the address pins ( $A_0$  through  $A_{12}$ ). Reading the device is accomplished by selecting the device and enabling the outputs,  $\overline{CE}_1$  and  $\overline{OE}$ active LOW, CE2 active HIGH, while WE remains inactive or HIGH. Under these conditions, the contents of the location addressed by the information on address pins are present on the eight data input/output pins.

The input/output pins remain in a high-impedance state unless the chip is selected, outputs are enabled, and write enable (WE) is HIGH. A die coat is used to insure alpha immunity.



### Selection Guide[1]

	7C185–12	7C185-15	7C185-20	7C185-25	7C185-35
Maximum Access Time (ns)	12	15	20	25	35
Maximum Operating Current (mA)	140	130	110	100	100
Maximum Standby Current (mA)	40/15	40/15	20/15	20/15	20/15

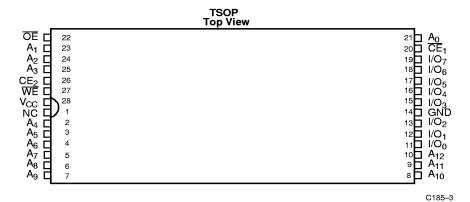
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### Note:

1. For military specifications, see the CY7C185A/CY7C186A datasheet.



## Pin Configurations (continued)



**Maximum Ratings** 

(Above which the useful life may be impaired. For user guidelines, not tested.) Storage Temperature ......-65°C to +150°C Ambient Temperature with Power Applied .......55°C to +125°C Supply Voltage to Ground Potential ..... -0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State<sup>[2]</sup>.....-0.5V to +7.0V DC Input Voltage<sup>[2]</sup>......-0.5V to +7.0V

Static Discharge Voltage ......>2001V (per MIL-STD-883, Method 3015) Latch-Up Current >200 mA

## **Operating Range**

Range	Ambient Temperature	V <sub>cc</sub>
Commercial	0°C to +70°C	5V ± 10%

### Electrical Characteristics Over the Operating Range

			7C18	35–12	7C185-15		
Parameter	Description	Test Conditions	Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA	2.4		2.4		٧
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA		0.4		0.4	٧
V <sub>IH</sub>	Input HIGH Voltage		2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	٧
V <sub>IL</sub>	Input LOW Voltage <sup>[2]</sup>		-0.5	0.8	-0.5	0.8	٧
I <sub>IX</sub>	Input Load Current	$GND \le V_I \le V_{CC}$	-5	+5	-5	+5	μΑ
l <sub>OZ</sub>	Output Leakage Current	$\begin{aligned} &\text{GND} \leq V_I \leq V_{CC}, \\ &\text{Output Disabled} \end{aligned}$	-5	+5	<b>-</b> 5	+5	μA
l <sub>OS</sub>	Output Short Circuit Current <sup>[3]</sup>	V <sub>CC</sub> = Max., V <sub>OUT</sub> = GND		-300		-300	mA
Icc	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max., I <sub>OUT</sub> = 0 mA		140		130	mA
I <sub>SB1</sub>	Automatic Power-Down Current	Max. V <sub>CC</sub> , <del>CE</del> <sub>1</sub> ≥ V <sub>IH</sub> or CE <sub>2</sub> ≤ V <sub>IL</sub> Min. Duty Cycle=100%	40		40	mA	
I <sub>SB2</sub>	Automatic Power-Down Current	$\begin{aligned} &\text{Max. V}_{CC}, \ \overline{CE}_1 \geq V_{CC} - 0.3V, \\ &\text{or } CE_2 \leq 0.3V \\ &V_{IN} \geq V_{CC} - 0.3V \text{ or } V_{IN} \leq 0.3V \end{aligned}$	15		15	mA	

Shaded areas contain preliminary information.

Notes:

Minimum voltage is equal to -3.0V for pulse durations less than 30 ns.

-Not more than 1 output should be shorted at one time. Duration of the short circuit should not exceed 30 seconds.



## Electrical Characteristics Over the Operating Range (continued)

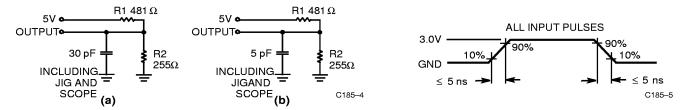
			7C185–20		7C185	<b>–25, 35</b>		
Parameter	Description	Test Conditions	Min.	Max.	Min.	Max.	Unit	
V <sub>OH</sub>	Output HIGH Voltage	V <sub>CC</sub> = Min., I <sub>OH</sub> = -4.0 mA	2.4		2.4		V	
V <sub>OL</sub>	Output LOW Voltage	V <sub>CC</sub> = Min., I <sub>OL</sub> = 8.0 mA		0.4		0.4	V	
V <sub>IH</sub>	Input HIGH Voltage		2.2	V <sub>CC</sub>	2.2	V <sub>CC</sub>	V	
V <sub>IL</sub>	Input LOW Voltage <sup>[2]</sup>		-0.5	0.8	-0.5	0.8	V	
I <sub>IX</sub>	Input Load Current	$GND \le V_I \le V_{CC}$	-5	+5	<del>-</del> 5	+5	μΑ	
loz	Output Leakage Current	$\begin{aligned} &\text{GND} \leq V_I \leq V_{CC}, \\ &\text{Output Disabled} \end{aligned}$	-5	+5	<del>-</del> 5	+5	μА	
los	Output Short Circuit Current <sup>[3]</sup>	V <sub>CC</sub> = Max., V <sub>OUT</sub> = GND		-300		-300	mA	
Icc	V <sub>CC</sub> Operating Supply Current	V <sub>CC</sub> = Max., I <sub>OUT</sub> = 0 mA		110		100	mA	
I <sub>SB1</sub>	Automatic Power-Down Current	Max. V <sub>CC</sub> , <del>CE</del> <sub>1</sub> ≥ V <sub>IH or</sub> CE <sub>2</sub> ≤ V <sub>IL</sub> Min. Duty Cycle=100%		20		20	mA	
I <sub>SB2</sub>	Automatic Power-Down Current	$\begin{aligned} &\text{Max. V}_{CC},  \overline{CE}_1 \geq V_{CC} - 0.3V \\ &\text{or } CE_2 \leq 0.3V \\ &V_{IN} \geq V_{CC} - 0.3V \text{ or } V_{IN} \leq 0.3V \end{aligned}$		15		15	mA	

# Capacitance<sup>[4]</sup>

Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	T <sub>A</sub> = 25°C, f = 1 MHz,	7	pF
C <sub>OUT</sub>	Output Capacitance	$V_{CC} = 5.0V$	7	pF

#### Note

### **AC Test Loads and Waveforms**



Equivalent to: THÉVENIN EQUIVALENT

OUTPUT• 167Ω 1.73V

<sup>4.</sup> Tested initially and after any design or process changes that may affect these parameters.



## Switching Characteristics Over the Operating Range<sup>[5]</sup>

		7C18	85–12	7C185-15		7C185-20		7C185-25		7C185-35		
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Unit
READ CYC	LE	100000000000000000000000000000000000000		,								
t <sub>RC</sub>	Read Cycle Time	12		15		20		25		35		ns
t <sub>AA</sub>	Address to Data Valid		12		15		20		25		35	ns
t <sub>OHA</sub>	Data Hold from Address Change	3		3		5		5		5		ns
t <sub>ACE1</sub>	CE₁ LOW to Data Valid		12		15		20		25		35	ns
t <sub>ACE2</sub>	CE <sub>2</sub> HIGH to Data Valid		12		15		20		25		35	ns
t <sub>DOE</sub>	OE LOW to Data Valid		6		8		9		12		15	ns
t <sub>LZOE</sub>	OE LOW to Low Z	2		3		3		3		3		ns
t <sub>HZOE</sub>	OE HIGH to High Z <sup>[6]</sup>		6		7		8		10		10	ns
t <sub>LZCE1</sub>	CE₁ LOW to Low Z <sup>[7]</sup>	3		3		5		5		5		ns
t <sub>LZCE2</sub>	CE <sub>2</sub> HIGH to Low Z	3		3		3		3		3		ns
t <sub>HZCE</sub>	CE <sub>1</sub> HIGH to High Z <sup>[6, 7]</sup> CE <sub>2</sub> LOW to High Z		6		7		8		10		10	ns
t <sub>PU</sub>	CE <sub>1</sub> LOW to Power-Up CE <sub>2</sub> to HIGH to Power-Up	0		0		0		0		0		ns
t <sub>PD</sub>	CE <sub>1</sub> HIGH to Power-Down CE <sub>2</sub> LOW to Power-Down		12		15		20		20		20	ns
WRITE CYC	LE <sup>[8]</sup>	I		:	ı							1
t <sub>WC</sub>	Write Cycle Time	12		15		20		25		35		ns
t <sub>SCE1</sub>	CE <sub>1</sub> LOW to Write End	8		12		15		20		20		ns
t <sub>SCE2</sub>	CE <sub>2</sub> HIGH to Write End	8		12		15		20		20		ns
t <sub>AW</sub>	Address Set-Up to Write End	9		12		15		20		25		ns
t <sub>HA</sub>	Address Hold from Write End	0		0		0		0		0		ns
t <sub>SA</sub>	Address Set-Up to Write Start	0		0		0		0		0		ns
t <sub>PWE</sub>	WE Pulse Width	8		12		15		15		20		ns
t <sub>SD</sub>	Data Set-Up to Write End	6		8		10		10		12		ns
t <sub>HD</sub>	Data Hold from Write End	0		0		0		0		0		ns
t <sub>HZWE</sub>	WE LOW to High Z <sup>[6]</sup>		6		7		7		7		8	ns
t <sub>LZWE</sub>	WE HIGH to Low Z	3		3		5		5		5		ns

Shaded areas contain preliminary information.

Notes:

<sup>5.</sup> 

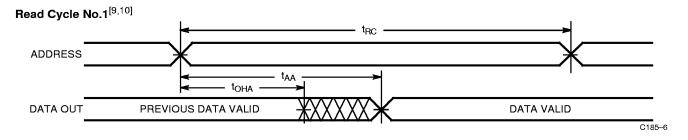
Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified  $l_{OL}/l_{OH}$  and 30-pF load capacitance.

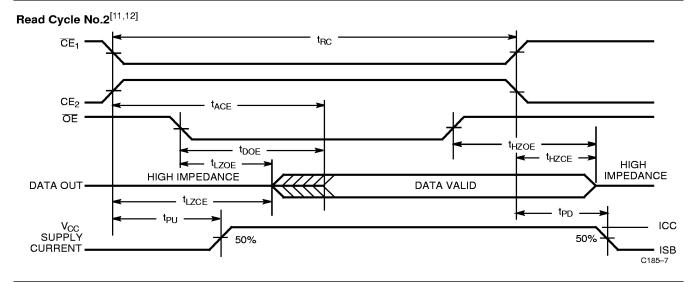
†HZOE, †HZOE, and †HZWE are specified with  $C_L = 5$  pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady state voltage. At any given temperature and voltage condition, †HZCE is less than †LZCE1 and †LZCE2 for any given device.

The internal write time of the memory is defined by the overlap of  $CE_1$  LOW,  $CE_2$  HIGH, and WE LOW. All 3 signals must be active to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

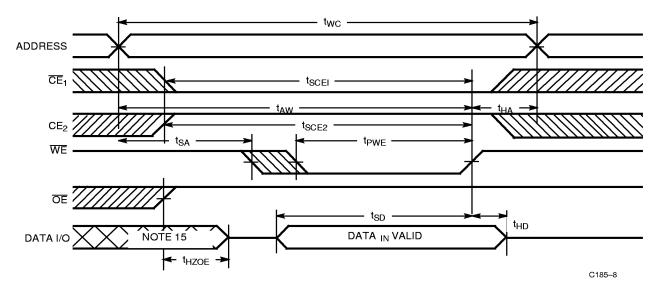


## **Switching Waveforms**





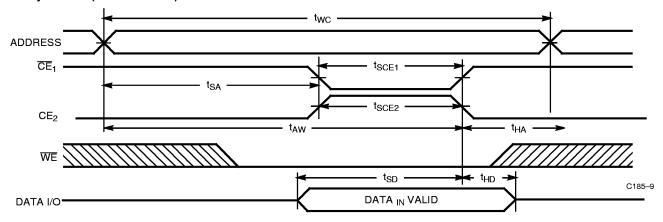
# Write CycleNo.1 ( $\overline{\text{WE}}$ Controlled) $^{[10,12]}$



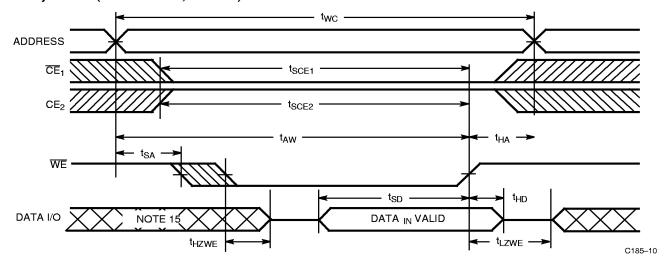


## Switching Waveforms (continued)

## Write Cycle no.2 (CE Controlled)[12,13,15]



# Write Cycle No.3 (WE Controlled, $\overline{\text{OE}}$ LOW)[12,13,14,15]



#### Notes:

- Device is continuously selected.  $\overline{OE}$ ,  $\overline{CE}_1 = V_{IL}$ .  $\overline{CE}_2 = V_{IH}$ .

  WE is HIGH for read cycle.

  Data I/O is High Z if  $\overline{OE} = V_{IH}$ ,  $\overline{CE}_1 = V_{IH}$ ,  $\overline{WE} = V_{IL}$  or  $\overline{CE}_2 = V_{IL}$ .

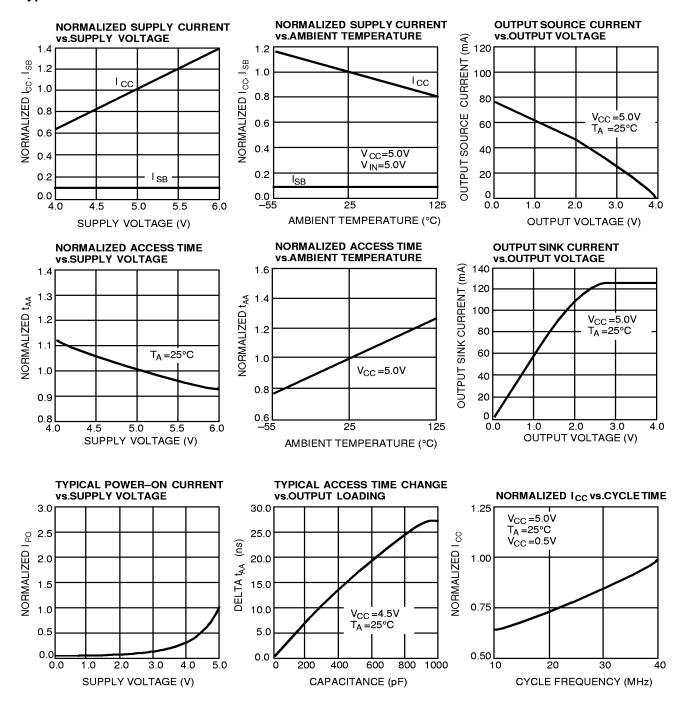
  The internal write time of the memory is defined by the overlap of  $\overline{CE}_1$  LOW,  $\overline{CE}_2$  HIGH and  $\overline{WE}$  LOW.  $\overline{CE}_1$  and  $\overline{WE}$  must be LOW and  $\overline{CE}_2$  must be HIGH to initiate write. A write can be terminated by  $\overline{CE}_1$  or  $\overline{WE}$  going HIGH or  $\overline{CE}_2$  going LOW. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.

  The minimum write cycle time for write cycle #3 ( $\overline{WE}$  controlled,  $\overline{OE}$  LOW) is the sum of  $t_{HZWE}$  and  $t_{SD}$ . If  $\overline{CE}_1$  goes HIGH or  $\overline{CE}_2$  goes LOW simultaneously with  $\overline{WE}$  HIGH, the output remains in a high-impedance state.

  During this period, the I/Os are in the output state and input signals should not be applied.



## Typical DC and AC Characteristics





# **Truth Table**

CE <sub>1</sub>	CE <sub>2</sub>	WE	ŌĒ	Input/Output	Mode
Н	Х	Х	Х	High Z	Deselect/Power-Down
Х	L	Х	Х	High Z	Deselect/Power-Down
L	Н	Н	L	Data Out	Read
L	Н	L	Х	Data In	Write
L	Н	Н	Н	High Z	Deselect

# **Address Designators**

Address Name	Address Function	Pin Number
A4	Х3	2
<b>A</b> 5	X4	3
A6	X5	4
<b>A</b> 7	X6	5
A8	X7	6
A9	Y1	7
A10	Y4	8
A11	Y3	9
A12	Y0	10
A0	Y2	21
A1	XO	23
A2	X1	24
A3	X2	25

# **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
12	2 CY7C185-12PC P21 28-Lead (300-Mil) Mo		28-Lead (300-Mil) Molded DIP	Commercial
	CY7C185-12VC	V21	28-Lead Molded SOJ	7
15	CY7C185-15PC	P21	28-Lead (300-Mil) Molded DIP	Commercial
	CY7C185-15VC	V21	28-Lead Molded SOJ	1
	CY7C185-15ZC	Z28	28-Lead Thin Small Outline Package	1
20	CY7C185-20PC	P21	28-Lead (300-Mil) Molded DIP	Commercial
	CY7C185-20VC	V21	28-Lead Molded SOJ	1
	CY7C185-20ZC	Z28	28-Lead Thin Small Outline Package	1
25	CY7C185-25PC	P21	28-Lead (300-Mil) Molded DIP	Commercial
	CY7C185-25VC	V21	28-Lead Molded SOJ	1
	CY7C185-25ZC	Z28	28-Lead Thin Small Outline Package	1
35	CY7C185-35PC	P21	28-Lead (300-Mil) Molded DIP	Commercial
	CY7C185-35VC	V21	28-Lead Molded SOJ	1
	CY7C185-35ZC	Z28	28-Lead Thin Small Outline Package	=

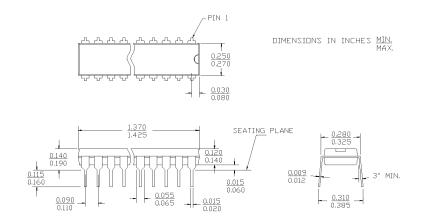
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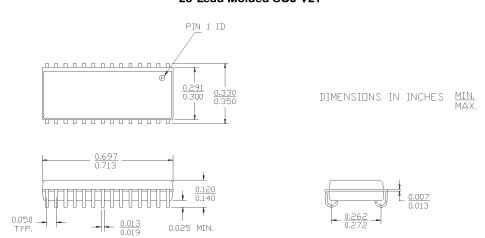


# **Package Diagrams**

### 28-Lead (300-Mil) Molded DIP P21



### 28-Lead Molded SOJ V21





### Package Diagrams (continued)

### 28-Lead Thin Small outline Package Z28

